

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 10032- CAA	5250.0, 5250000	5.18	4.45	33.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head 20.36 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-16 Sys5 B5.prn, 2024-Sep-16	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-18, 04:45	2024-09-18, 04:56
psSAR1g [W/Kg]	0.450	0.517
psSAR10g [W/Kg]	0.165	0.169
Power Drift [dB]	0.13	0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		59.7
Dist 3dB Peak [mm]		8.0





Figure C.7: SAR testing results for the A3186 at 5250 MHz Core 0



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 10032- CAA	5250.0, 5250000	5.18	4.45	33.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head 20.36 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-16 Sys5 B5.prn, 2024-Sep-16	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-18, 06:03	2024-09-18, 06:15
psSAR1g [W/Kg]	0.363	0.406
psSAR10g [W/Kg]	0.135	0.131
Power Drift [dB]	0.06	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		60.1
Dist 3dB Peak [mm]		7.6





Figure C.8: SAR testing results for the A3186 at 5250 MHz Core 1



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 10032- CAA	5850.0, 5850000	4.63	5.09	32.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head 20.36 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-16 Sys5 B5.prn, 2024-Sep-16	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-17, 20:47	2024-09-17, 20:58
psSAR1g [W/Kg]	0.375	0.445
psSAR10g [W/Kg]	0.141	0.142
Power Drift [dB]	0.03	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		55.1
Dist 3dB Peak [mm]		8.0





Figure C.9: SAR testing results for the A3186 at 5850 MHz Core 0



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 10032- CAA	5850.0, 5850000	4.63	5.09	32.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head 20.36 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-16 Sys5 B5.prn, 2024-Sep-16	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-17, 23:02	2024-09-17, 23:10
psSAR1g [W/Kg]	0.339	0.376
psSAR10g [W/Kg]	0.129	0.128
Power Drift [dB]	-0.02	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		55.7
Dist 3dB Peak [mm]		8.4





Figure C.10: SAR testing results for the A3186 at 5850 MHz Core 1



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 10032- CAA	5250.0, 5250000	5.18	4.51	34.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.42 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-18 SYS5 B5.prn, 2024-Sep-18	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-18, 23:04	2024-09-18, 23:13
psSAR1g [W/Kg]	0.189	0.226
psSAR10g [W/Kg]	0.068	0.073
Power Drift [dB]	0.20	0.19
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		57.5
Dist 3dB Peak [mm]		8.0





Figure C.11: SAR testing results for the A3186 at 5250 MHz Core 0



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 10032- CAA	5250.0, 5250000	5.18	4.51	34.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.42 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-18 SYS5 B5.prn, 2024-Sep-18	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-19, 00:25	2024-09-19, 00:33
psSAR1g [W/Kg]	0.161	0.169
psSAR10g [W/Kg]	0.057	0.054
Power Drift [dB]	0.14	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		59.1
Dist 3dB Peak [mm]		8.7





Figure C.12: SAR testing results for the A3186 at 5250 MHz Core 0



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 10032- CAA	5850.0, 5850000	4.63	5.18	33.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.42 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-18 SYS5 B5.prn, 2024-Sep-18	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-18, 13:45	2024-09-18, 13:54
psSAR1g [W/Kg]	0.159	0.176
psSAR10g [W/Kg]	0.056	0.052
Power Drift [dB]	-0.13	-0.42
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		54.3
Dist 3dB Peak [mm]		8.0





Figure C.13: SAR testing results for the A3186 at 5850 MHz Core 0



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 10032- CAA	5850.0, 5850000	4.63	5.18	33.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.42 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-18 SYS5 B5.prn, 2024-Sep-18	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-18, 15:34	2024-09-18, 15:43
psSAR1g [W/Kg]	0.134	0.139
psSAR10g [W/Kg]	0.047	0.042
Power Drift [dB]	0.33	-0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		53.9
Dist 3dB Peak [mm]		7.2





Figure C.14: SAR testing results for the A3186 at 5850 MHz Core 1



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 0	2405.0, 2405000	7.22	1.76	38.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.86 deg.C 2024-	EX3DV4 - SN7804,	DAE4ip Sn1786,
tilt) - 2102	Sep-18 SYS3 B3.prn, 2024-Sep-18	2024-08-14	2024-08-07

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-18, 11:38	2024-09-18, 11:50
psSAR1g [W/Kg]	0.707	0.721
psSAR10g [W/Kg]	0.360	0.342
Power Drift [dB]	-0.10	-0.10
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		76.5
Dist 3dB Peak [mm]		9.9





Figure C.15: SAR testing results for the A3186 at 2405 MHz Core 0



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 0	2480.0, 2480000	7.22	1.82	38.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.86 deg.C 2024-	EX3DV4 - SN7804,	DAE4ip Sn1786,
tilt) - 2102	Sep-18 SYS3 B3.prn, 2024-Sep-18	2024-08-14	2024-08-07

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-18, 14:11	2024-09-18, 14:23
psSAR1g [W/Kg]	0.707	0.739
psSAR10g [W/Kg]	0.337	0.310
Power Drift [dB]	0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		75.6
Dist 3dB Peak [mm]		8.0





Figure C.16: SAR testing results for the A3186 at 2480 MHz Core 1



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 0	2405.0, 2405000	7.22	1.76	38.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.86 deg.C 2024-	EX3DV4 - SN7804,	DAE4ip Sn1786,
tilt) - 2102	Sep-18 SYS3 B3.prn, 2024-Sep-18	2024-08-14	2024-08-07

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-18, 14:44	2024-09-18, 14:56
psSAR1g [W/Kg]	0.039	0.042
psSAR10g [W/Kg]	0.019	0.017
Power Drift [dB]	0.06	-0.10
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		73.5
Dist 3dB Peak [mm]		8.0





Figure C.17: SAR testing results for the A3186 at 2405 MHz Core 2



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 0	2405.0, 2405000	7.22	1.76	38.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.86 deg.C 2024-	EX3DV4 - SN7804,	DAE4ip Sn1786,
tilt) - 2102	Sep-18 SYS3 B3.prn, 2024-Sep-18	2024-08-14	2024-08-07

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-18, 18:01	2024-09-18, 18:13
psSAR1g [W/Kg]	0.235	0.243
psSAR10g [W/Kg]	0.120	0.115
Power Drift [dB]	-0.04	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		76.1
Dist 3dB Peak [mm]		9.9





Figure C.18: SAR testing results for the A3186 at 2405 MHz Core 0



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 0	2440.0, 2440000	7.22	1.79	38.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.86 deg.C 2024-	EX3DV4 - SN7804,	DAE4ip Sn1786,
tilt) - 2102	Sep-18 SYS3 B3.prn, 2024-Sep-18	2024-08-14	2024-08-07

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-18, 19:57	2024-09-18, 20:09
psSAR1g [W/Kg]	0.186	0.188
psSAR10g [W/Kg]	0.085	0.081
Power Drift [dB]	0.05	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		74.8
Dist 3dB Peak [mm]		8.6





Figure C.19: SAR testing results for the A3186 at 2440 MHz Core 1



Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	Custom Band	CW, 0	2405.0, 2405000	7.22	1.76	38.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.86 deg.C 2024-	EX3DV4 - SN7804,	DAE4ip Sn1786,
tilt) - 2102	Sep-18 SYS3 B3.prn, 2024-Sep-18	2024-08-14	2024-08-07

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-18, 14:44	2024-09-18, 14:56
psSAR1g [W/Kg]	0.039	0.042
psSAR10g [W/Kg]	0.019	0.017
Power Drift [dB]	0.06	-0.10
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		73.5
Dist 3dB Peak [mm]		8.0





Figure C.20: SAR testing results for the A3186 at 2405 MHz Core 2



Measurement Report for A3186, BACK, WLAN 2.4GHz, IEEE 802.11b WiFi 2.4 GHz (DSSS, 1 Mbps, 99pc duty cycle), Channel 1 (2412.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 2.4GHz	WLAN, 10415-AAA	2412.0, 1	7.22	1.76	38.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.86 deg.C 2024-	EX3DV4 - SN7804,	DAE4ip Sn1786,
tilt) - 2102	Sep-18 SYS3 B3.prn, 2024-Sep-18	2024-08-14	2024-08-07

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-18, 23:20	2024-09-18, 23:31
psSAR1g [W/Kg]	0.722	0.725
psSAR10g [W/Kg]	0.353	0.338
Power Drift [dB]	0.00	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		75.3
Dist 3dB Peak [mm]		9.0





Figure C.21: SAR testing results for the A3186 at 2412 MHz Core 0



Measurement Report for A3186, BACK, WLAN 2.4GHz, IEEE 802.11g WiFi 2.4 GHz (ERP-OFDM, 6 Mbps, 99pc duty cycle), Channel 6 (2437.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 2.4GHz	WLAN, 10416-AAA	2437.0, 6	7.22	1.78	38.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.86 deg.C 2024-	EX3DV4 - SN7804,	DAE4ip Sn1786,
tilt) - 2102	Sep-18 SYS3 B3.prn, 2024-Sep-18	2024-08-14	2024-08-07

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-19, 01:57	2024-09-19, 02:08
psSAR1g [W/Kg]	0.852	0.857
psSAR10g [W/Kg]	0.411	0.394
Power Drift [dB]	-0.01	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		74.4
Dist 3dB Peak [mm]		9.0





Figure C.22: SAR testing results for the A3186 at 2437 MHz Core 0



Measurement Report for A3186, BACK, WLAN 2.4GHz, IEEE 802.11b WiFi 2.4 GHz (DSSS, 1 Mbps, 99pc duty cycle), Channel 11 (2462.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 2.4GHz	WLAN, 10415-AAA	2462.0, 11	7.22	1.80	38.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.86 deg.C 2024-	EX3DV4 - SN7804,	DAE4ip Sn1786,
tilt) - 2102	Sep-18 SYS3 B3.prn, 2024-Sep-18	2024-08-14	2024-08-07

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-19, 04:38	2024-09-19, 04:50
psSAR1g [W/Kg]	0.607	0.608
psSAR10g [W/Kg]	0.283	0.260
Power Drift [dB]	0.02	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		75.0
Dist 3dB Peak [mm]		8.0





Figure C.23: SAR testing results for the A3186 at 2462 MHz Core 1



Measurement Report for A3186, BACK, WLAN 2.4GHz, IEEE 802.11g WiFi 2.4 GHz (ERP-OFDM, 6 Mbps, 99pc duty cycle), Channel 6 (2437.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 2.4GHz	WLAN, 10416-AAA	2437.0, 6	7.22	1.78	38.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.86 deg.C 2024-	EX3DV4 - SN7804,	DAE4ip Sn1786,
tilt) - 2102	Sep-18 SYS3 B3.prn, 2024-Sep-18	2024-08-14	2024-08-07

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-19, 06:14	2024-09-19, 06:25
psSAR1g [W/Kg]	0.697	0.704
psSAR10g [W/Kg]	0.326	0.303
Power Drift [dB]	0.02	0.10
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		74.9
Dist 3dB Peak [mm]		8.6





Figure C.24: SAR testing results for the A3186 at 2437 MHz Core 1


Measurement Report for A3186, BACK, WLAN 2.4GHz, IEEE 802.11n (HT Mixed, 6.5 Mbps, BPSK), Channel 6 (2437.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 2.4GHz	WLAN, 10196- CAD	, 6	7.22	1.78	38.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.86 deg.C 2024-	EX3DV4 - SN7804,	DAE4ip Sn1786,
tilt) - 2102	Sep-18 SYS3 B3.prn, 2024-Sep-18	2024-08-14	2024-08-07

Scans Setup

	Area Scan	Zoom Scan	Zoom Scan
Grid Extents [mm]	x 260.0	30.0 x 30.0 x 30.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4	1.4
Graded Grid	n/a	Yes	Yes
Grading Ratio	n/a	1.5	1.5
MAIA	N/A	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured	Measured

	Area Scan	Zoom Scan	Zoom Scan
Date	2024-09-19, 11:33	2024-09-19, 11:44	2024-09-19, 11:56
psSAR1g [W/kg]	0.640	0.630	0.681
psSAR10g [W/kg]	0.326	0.277	0.320
psAPD (4.0cm2, sq) [W/m2]		n/a	n/a
Power Drift [dB]	0.00	-0.01	-0.01
Power Scaling	Disabled	Disabled	Disabled
Scaling Factor [dB]			
TSL Correction	Positive only	Positive only	Positive only
M2/M1 [%]		74.8	75.1
Dist 3dB Peak [mm]		8.6	9.0





Figure C.25: SAR testing results for the A3186 at 2437 MHz Core 0 & Core 1



Measurement Report for A3186, BACK, U-NII-1, U-NII-2A, IEEE 802.11ac WiFi (80MHz, MCS0, 99pc duty cycle), Channel 42 (5210.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	U-NII-1, U-NII-2A	WLAN, 10544-AAC	5210.0, 42	5.18	4.47	34.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.42 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-18 SYS5 B5.prn, 2024-Sep-18	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-19, 06:53	2024-09-19, 07:01
psSAR1g [W/Kg]	0.462	0.535
psSAR10g [W/Kg]	0.170	0.175
Power Drift [dB]	0.05	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		59.7
Dist 3dB Peak [mm]		7.6





Figure C.26: SAR testing results for the A3186 at 5210 MHz Core 0



Measurement Report for A3186, BACK, U-NII-1, U-NII-2A, IEEE 802.11ac WiFi (80MHz, MCS0, 99pc duty cycle), Channel 42 (5210.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	U-NII-1, U-NII-2A	WLAN, 10544-AAC	5210.0, 42	5.18	4.47	34.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.42 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-18 SYS5 B5.prn, 2024-Sep-18	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-19, 07:13	2024-09-19, 07:21
psSAR1g [W/Kg]	0.576	0.622
psSAR10g [W/Kg]	0.210	0.214
Power Drift [dB]	0.11	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		60.9
Dist 3dB Peak [mm]		8.0





Figure C.27: SAR testing results for the A3186 at 5210 MHz Core 1



Measurement Report for A3186, BACK, WLAN 5GHz, IEEE 802.11ac WiFi (80MHz, MCS0, 99pc duty cycle), Channel 42 (5210.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 5GHz	WLAN, 10544-AAC	, 42	5.18	4.47	34.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.42 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-18 SYS5 B5.prn, 2024-Sep-18	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan	Zoom Scan
Grid Extents [mm]	x 260.0	22.0 x 22.0 x 22.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4	1.4
Graded Grid	n/a	Yes	Yes
Grading Ratio	n/a	1.4	1.4
MAIA	Y	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured	Measured

	Area Scan	Zoom Scan	Zoom Scan
Date	2024-09-19, 11:40	2024-09-19, 11:52	2024-09-19, 12:01
psSAR1g [W/Kg]	0.477	0.509	0.493
psSAR10g [W/Kg]	0.176	0.178	0.166
Power Drift [dB]	0.10	0.07	-0.03
Power Scaling	Disabled	Disabled	Disabled
Scaling Factor [dB]			
TSL Correction	Positive only	Positive only	Positive only
M2/M1 [%]		60.7	59.3
Dist 3dB Peak [mm]		9.2	8.0





Figure C.28: SAR testing results for the A3186 at 5210 MHz Core 0 & Core 1



Measurement Report for A3186, BACK, U-NII-1, U-NII-2A, IEEE 802.11ac WiFi (80MHz, MCS0, 99pc duty cycle), Channel 58 (5290.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	U-NII-1, U-NII-2A	WLAN, 10544-AAC	5290.0, 58	5.01	4.55	34.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.42 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-18 SYS5 B5.prn, 2024-Sep-18	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-19, 06:34	2024-09-19, 06:41
psSAR1g [W/Kg]	0.530	0.598
psSAR10g [W/Kg]	0.194	0.196
Power Drift [dB]	0.12	-0.13
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		59.9
Dist 3dB Peak [mm]		7.9





Figure C.29: SAR testing results for the A3186 at 5290 MHz Core 0



Measurement Report for A3186, BACK, WLAN 5GHz, IEEE 802.11n (HT Mixed, 13.5 Mbps, BPSK), Channel 62 (5310.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 5GHz	WLAN, 10117-CAD	5310.0, 62	5.01	4.57	34.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.71 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-20 SYS5 B5.prn, 2024-Sep-20	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-21, 01:15	2024-09-21, 01:23
psSAR1g [W/Kg]	0.705	0.771
psSAR10g [W/Kg]	0.270	0.273
Power Drift [dB]	0.02	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		60.7
Dist 3dB Peak [mm]		8.7





Figure C.30: SAR testing results for the A3186 at 5310 MHz Core 1



Measurement Report for A3186, BACK, WLAN 5GHz, IEEE 802.11n (HT Mixed, 13.5 Mbps, BPSK), Channel 54 (5270.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Expectate conta							
Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 5GHz	WLAN, 10117-CAD	, 54	5.01	4.53	34.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.42 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-18 SYS5 B5.prn, 2024-Sep-18	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan	Zoom Scan
Grid Extents [mm]	x 260.0	22.0 x 22.0 x 22.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4	1.4
Graded Grid	n/a	Yes	Yes
Grading Ratio	n/a	1.4	1.4
MAIA	Y	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured	Measured

	Area Scan	Zoom Scan	Zoom Scan
Date	2024-09-19, 14:31	2024-09-19, 14:42	2024-09-19, 14:54
psSAR1g [W/Kg]	0.592	0.623	0.516
psSAR10g [W/Kg]	0.225	0.222	0.176
Power Drift [dB]	0.03	0.04	0.04
Power Scaling	Disabled	Disabled	Disabled
Scaling Factor [dB]			
TSL Correction	Positive only	Positive only	Positive only
M2/M1 [%]		61.3	60.1
Dist 3dB Peak [mm]		8.8	8.8





Figure C.31: SAR testing results for the A3186 at 5270 MHz Core 0 & Core 1



Measurement Report for A3186, BACK, WLAN 5GHz, IEEE 802.11ac WiFi (80MHz, MCS0, 99pc duty cycle), Channel 138 (5690.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 5GHz	WLAN, 10544-AAC	5690.0, 138	4.56	5.00	33.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.42 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-18 SYS5 B5.prn, 2024-Sep-18	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-19, 19:00	2024-09-19, 19:10
psSAR1g [W/Kg]	0.710	0.780
psSAR10g [W/Kg]	0.245	0.245
Power Drift [dB]	0.11	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		57.2
Dist 3dB Peak [mm]		7.9





Figure C.32: SAR testing results for the A3186 at 5610 MHz Core 0



Measurement Report for A3186, BACK, WLAN 5GHz, IEEE 802.11ac WiFi (80MHz, MCS0, 99pc duty cycle), Channel 138 (5690.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 5GHz	WLAN, 10544-AAC	5690.0, 138	4.56	5.00	33.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.42 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-18 SYS5 B5.prn, 2024-Sep-18	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-19, 21:33	2024-09-19, 21:42
psSAR1g [W/Kg]	0.802	0.853
psSAR10g [W/Kg]	0.300	0.288
Power Drift [dB]	0.07	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		57.9
Dist 3dB Peak [mm]		8.0





Figure C.33: SAR testing results for the A3186 at 5690 MHz Core 0 & Core 1



Measurement Report for A3186, BACK, WLAN 5GHz, IEEE 802.11ac WiFi (80MHz, MCS0, 99pc duty cycle), Channel 138 (5690.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 5GHz	WLAN, 10544-AAC	, 138	4.56	5.00	33.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.42 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-18 SYS5 B5.prn, 2024-Sep-18	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan	Zoom Scan
Grid Extents [mm]	x 260.0	22.0 x 22.0 x 22.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4	1.4
Graded Grid	n/a	Yes	Yes
Grading Ratio	n/a	1.4	1.4
MAIA	Y	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured	Measured

	Area Scan	Zoom Scan	Zoom Scan
Date	2024-09-19, 23:07	2024-09-19, 23:16	2024-09-19, 23:25
psSAR1g [W/Kg]	0.817	0.840	0.780
psSAR10g [W/Kg]	0.304	0.284	0.246
Power Drift [dB]	0.05	-0.04	0.01
Power Scaling	Disabled	Disabled	Disabled
Scaling Factor [dB]			
TSL Correction	Positive only	Positive only	Positive only
M2/M1 [%]		58.2	57.1
Dist 3dB Peak [mm]		7.9	8.0





Figure C.34: SAR testing results for the A3186 at 5690 MHz Core 0 & Core 1



Measurement Report for A3186, BACK, WLAN 5GHz, IEEE 802.11ac WiFi (80MHz, MCS0, 99pc duty cycle), Channel 155 (5775.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 5GHz	WLAN, 10544-AAC	5775.0, 155	4.63	5.08	33.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.71 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-20 SYS5 B5.prn, 2024-Sep-20	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-20, 11:17	2024-09-20, 11:26
psSAR1g [W/Kg]	0.462	0.528
psSAR10g [W/Kg]	0.158	0.165
Power Drift [dB]	0.38	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		54.9
Dist 3dB Peak [mm]		8.0





Figure C.35: SAR testing results for the A3186 at 5775 MHz Core 0



Measurement Report for A3186, BACK, WLAN 5GHz, IEEE 802.11ac WiFi (80MHz, MCS0, 99pc duty cycle), Channel 155 (5775.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 5GHz	WLAN, 10544-AAC	5775.0, 155	4.63	5.08	33.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.71 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-20 SYS5 B5.prn, 2024-Sep-20	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	140.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-20, 11:38	2024-09-20, 11:50
psSAR1g [W/Kg]	0.508	0.554
psSAR10g [W/Kg]	0.184	0.185
Power Drift [dB]	0.33	0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		56.0
Dist 3dB Peak [mm]		8.7





Figure C.36: SAR testing results for the A3186 at 5775 MHz Core 1



Measurement Report for A3186, BACK, WLAN 5GHz, IEEE 802.11ac WiFi (80MHz, MCS0, 99pc duty cycle), Channel 155 (5775.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	WLAN 5GHz	WLAN, 10544-AAC	, 155	4.63	5.08	33.5

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.71 deg.C 2024-	EX3DV4 - SN7805,	DAE4ip Sn1785,
tilt) - 2202	Sep-20 SYS5 B5.prn, 2024-Sep-20	2024-02-14	2024-02-13

Scans Setup

	Area Scan	Zoom Scan	Zoom Scan
Grid Extents [mm]	x 260.0	22.0 x 22.0 x 22.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4	1.4
Graded Grid	n/a	Yes	Yes
Grading Ratio	n/a	1.4	1.4
MAIA	Y	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured	Measured

	Area Scan	Zoom Scan	Zoom Scan
Date	2024-09-20, 12:05	2024-09-20, 12:14	2024-09-20, 12:25
psSAR1g [W/Kg]	0.526	0.582	0.574
psSAR10g [W/Kg]	0.185	0.188	0.195
Power Drift [dB]	0.15	-0.14	0.17
Power Scaling	Disabled	Disabled	Disabled
Scaling Factor [dB]			
TSL Correction	Positive only	Positive only	Positive only
M2/M1 [%]		55.7	57.1
Dist 3dB Peak [mm]		8.2	8.8





Figure C.37: SAR testing results for the A3186 at 5775 MHz Core 0 & Core 1



Measurement Report for A3186, BACK, U-NII-5, IEEE 802.11ax (160MHz, MCS0, 99pc duty cycle), Channel 15 (6025.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Expectate conta							
Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	U-NII- 5	WLAN, 10755-AAC	6025.0, 15	5.61	5.29	32.4

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head 20.36 deg.C 2024-	EX3DV4 - SN7809,	DAE4ip Sn1789,
tilt) - 2203	Sep-16 SYS6 B6.prn, 2024-Sep-16	2024-05-13	2024-05-03

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	153.0 x 204.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-18, 05:07	2024-09-18, 05:16
psSAR1g [W/Kg]	0.241	0.260
psSAR10g [W/Kg]	0.082	0.084
psAPD (4.0cm2, sq) [W/m2]		1.92
Power Drift [dB]	-0.05	-0.16
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		50.8
Dist 3dB Peak [mm]		8.2



missing Figure C.38: SAR testing results for the A3186 at 6025 MHz Core 0



Measurement Report for A3186, BACK, U-NII-5, IEEE 802.11ax (160MHz, MCS0, 99pc duty cycle), Channel 15 (6025.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	U-NII- 5	WLAN, 10755-AAC	6025.0, 15	5.61	5.35	33.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.82 deg.C 2024-	EX3DV4 - SN7809,	DAE4ip Sn1789,
tilt) - 2203	Sep-18 SYS6 B6.prn, 2024-Sep-18	2024-05-13	2024-05-03

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	153.0 x 204.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-18, 14:03	2024-09-18, 14:16
psSAR1g [W/Kg]	0.229	0.242
psSAR10g [W/Kg]	0.081	0.083
psAPD (4.0cm2, sq) [W/m2]		1.87
Power Drift [dB]	0.08	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		51.3
Dist 3dB Peak [mm]		8.2





Figure C.39: SAR testing results for the A3186 at 6025 MHz Core 1



Measurement Report for A3186, BACK, U-NII-5, IEEE 802.11ax (160MHz, MCS0, 99pc duty cycle), Channel 15 (6025.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	U-NII- 5	WLAN, 10755-AAC	, 15	5.61	5.35	33.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.82 deg.C 2024-	EX3DV4 - SN7809,	DAE4ip Sn1789,
tilt) - 2203	Sep-18 SYS6 B6.prn, 2024-Sep-18	2024-05-13	2024-05-03

Scans Setup

	Area Scan	Zoom Scan	Zoom Scan
Grid Extents [mm]	x 289.0	22.0 x 22.0 x 22.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4	1.4
Graded Grid	n/a	Yes	Yes
Grading Ratio	n/a	1.4	1.4
MAIA	Y	Y	Y
Surface Detection	VMS + 6p	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured	Measured

	Area Scan	Zoom Scan	Zoom Scan
Date	2024-09-18, 18:35	2024-09-18, 18:47	2024-09-18, 19:01
psSAR1g [W/kg]	0.239	0.260	0.244
psSAR10g [W/kg]	0.083	0.084	0.083
psAPD (4.0cm2, sq) [W/m2]		1.92	1.89
Power Drift [dB]	0.10	0.14	-0.08
Power Scaling	Disabled	Disabled	Disabled
Scaling Factor [dB]			
TSL Correction	Positive only	Positive only	Positive only
M2/M1 [%]		49.9	50.9
Dist 3dB Peak [mm]		8.2	8.5





Figure C.40: SAR testing results for the A3186 at 6025 MHz Core 0 & Core 1



Measurement Report for A3186, BACK, U-NII-5, IEEE 802.11ax (160MHz, MCS0, 99pc duty cycle), Channel 47 (6185.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	U-NII- 5	WLAN, 10755-AAC	6185.0, 47	5.61	5.47	32.1

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head 20.36 deg.C 2024-	EX3DV4 - SN7809,	DAE4ip Sn1789,
tilt) - 2203	Sep-16 SYS6 B6.prn, 2024-Sep-16	2024-05-13	2024-05-03

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	153.0 x 204.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	n/a	Yes
Grading Ratio	n/a	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-18, 05:30	2024-09-18, 05:39
psSAR1g [W/Kg]	0.261	0.277
psSAR10g [W/Kg]	0.089	0.091
psAPD (4.0cm2, sq) [W/m2]		2.07
Power Drift [dB]	0.01	-0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		50.4
Dist 3dB Peak [mm]		8.2





Figure C.41: APD testing results for the A3186 at 6185 MHz Core 0



Measurement Report for A3186, BACK, U-NII-7, IEEE 802.11ax (40MHz, MCS0, 99pc duty cycle), Channel 179 (6845.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Laptop

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	U-NII- 7	WLAN, 10707-AAC	6845.000, 179	5.61	6.30	31.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.82 deg.C 2024-	EX3DV4 - SN7809,	DAE4ip Sn1789,
tilt) - 2203	Sep-18 SYS6 B6.prn, 2024-Sep-18	2024-05-13	2024-05-03

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	153.0 x 204.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2024-09-19, 03:55	2024-09-19, 04:09
psSAR1g [W/Kg]	0.343	0.370
psSAR10g [W/Kg]	0.113	0.117
psAPD (4.0cm2, sq) [W/m2]		2.68
Power Drift [dB]	0.05	-0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	Positive only	Positive only
M2/M1 [%]		46.7
Dist 3dB Peak [mm]		7.7





Figure C.42: APD testing results for the A3186 at 6845 MHz Core 1


Measurement Report for A3186, BACK, U-NII-7, IEEE 802.11ax (40MHz, MCS0, 99pc duty cycle), Channel 179 (6845.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	355.0 x 248.0 x 15.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 0.00	U-NII- 7	WLAN, 10707-AAC	6845.000, 179	5.61	6.30	31.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe	HBBL-600-10000 DAK 3.5 Head ELI 20.82 deg.C 2024-	EX3DV4 - SN7809,	DAE4ip Sn1789,
tilt) - 2203	Sep-18 SYS6 B6.prn, 2024-Sep-18	2024-05-13	2024-05-03

Scans Setup

	Area Scan	Zoom Scan	Zoom Scan
Grid Extents [mm]	x 289.0	22.0 x 22.0 x 22.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.5 x 8.5	3.4 x 3.4 x 1.4	3.4 x 3.4 x 1.4
Sensor Surface [mm]	3.0	1.4	1.4
Graded Grid	N/A	Yes	Yes
Grading Ratio	N/A	1.4	1.4
MAIA	Y	Y	Y
Surface Detection	VMS + 6p	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan	Zoom Scan
Date	2024-09-19, 04:27	2024-09-19, 04:40	2024-09-19, 04:54
psSAR1g [W/kg]	0.332	0.332	0.322
psSAR10g [W/kg]	0.109	0.105	0.101
psAPD (4.0cm2, sq) [W/m2]		2.40	2.31
Power Drift [dB]	-0.04	-0.08	-0.08
Power Scaling	Disabled	Disabled	Disabled
Scaling Factor [dB]			
TSL Correction	Positive only	Positive only	Positive only
M2/M1 [%]		46.3	45.5
Dist 3dB Peak [mm]		8.2	7.4





Figure C.43: APD testing results for the A3186 at 6845 MHz Core 0 & Core 1



Measurement Report for A3186, BACK, U-NII-7, IEEE 802.11ax (40MHz, MCS0, 99pc duty cycle), Channel 179 (6845.0 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
A3186,	360.0 x 250.0 x 15.0		Laptop

Exposure Conditions

Phantom Section	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor
5G	BACK, 2.00	U-NII- 7	WLAN, 10707- AAC	6845.0, 179	1.0

Hardware Setup

Phantom	Medium	Probe, Calibration Date	DAE, Calibration Date
mmWave - 1112	Air -	EUmmWV4 - SN9641_F1-55GHz, 2023-10-24	DAE4ip Sn1786, 2024-08-07

Scans Setup

Scan Type	5G Scan
Grid Extents [mm]	70.0 x 110.0
Grid Steps [lambda]	0.04660656853857782 x 0.04660656853857782
Sensor Surface [mm]	2.0
MAIA	Y

Measurement Results

Scan Type	5G Scan
Date	2024-09-20, 18:55
Avg. Area [cm ²]	4.00
psPDn+ [W/m²]	3.63
psPDtot+ [W/m ²]	6.65
psPDmod+ [W/m ²]	9.06
E _{max} [V/m]	117
Power Drift [dB]	-0.18





Figure C.44: iPD testing results for the A3186 at 6845 MHz Core 1



ANNEX D

THREAD TECHNOLOGY DUTY FACTOR CORRECTION



A3186 Thread Scaling Rationale

The measured SAR Results for the Thread technology, as detailed in this document, are scaled down to 60.81% to adjust for the normal operating conditions of this technology as shown in figure 13. With the measured SAR Results having been taken with the device operating in a test mode, on a fixed channel with 100% duty cycle, as shown below in figure 12.



Figure 9 - Thread ePA - Frequency of 2405 MHz (100% Duty Cycle)



Figure 10 - Thread ePA - Frequency of 2405 MHz (60.81% Duty Cycle)